## Applicant(s)/Patent Under Application/Control No. Reexamination 10/681,647 KIM ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Hiep Nguyen 2816 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 341/150 US-4,384,277 05-1983 Allgood et al. Α US-6,835,884 12-2004 Iwamoto et al. 84/609 В US-С D US-US-E US-F US-G US-Н USı US-US-Κ US-L US-

## **FOREIGN PATENT DOCUMENTS**

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